## Notice of References Cited

Application/Control No. 10/661,314	Applicant(s)/Patent Under Reexamination SHI ET AL.		
Examiner	Art Unit		
William J. Deane	2614	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,826,159	11-2004	Shaffer et al.	370/260
*	В	US-7,283,788	10-2007	Posa et al.	455/41.2
*	С	US-2003/0138119	07-2003	Pocino et al.	381/119
*	D	US-6,304,648	10-2001	Chang, Young-Fu	379/202.01
	Е	US-			
	F	US-			
	O	US-			
	Ξ	US-			
	ı	US-			
	7	US-			
	K	US-	,		
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 292 090	12-2003	U.S.	Taib et al.	H04M 3/56
	0					
	Р					
	σ					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	V			
	w			
	x			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.